§ 32.102

the device with an applied double amplitude of 0.060 inch and the frequency cycling between 10 and 55 cycles per second in 1-minute cycles for the periods and temperature conditions shown in Table I. Devices to be installed in aircraft without vibration isolators shall be tested by applying vibration along each of three mutually perpendicular axes of the device with an applied double amplitude of 0.036 inch or an applied acceleration of 10G, whichever is the limiting value, and the frequency cycling between 10 and 500 cycles per second in 15-minute cycles for the periods and temperature conditions shown in Table I.

- (c) Accelerated weathering tests. The device shall be subjected to 100 hours of accelerated weathering in a suitable weathering machine. Panels of Corex D glass shall surround the arc to cut off the ultraviolet radiation below a wavelength of 2,700 angstroms. The light of the carbon arcs shall fall directly on the face of the device. The temperature at the sample shall be maintained at 50°C. plus or minus 3°C. Temperature measurements shall be made with a black panel thermometer.
- (d) Shock test. The device shall be dropped upon a concrete or iron surface in a 3-foot free gravitational fall, or shall be subjected to equivalent treatment in a test device simulating such a free fall. The drop test shall be repeated 100 times from random orientations.
- (e) Hermetic seal and waterproof test. On completion of all other tests prescribed by this section, the device shall be immersed in 30 inches of water for 24 hours and shall show no visible evidence of water entry. Absolute pressure of the air above the water shall then be reduced to 1 inch of mercury. Lowered pressure shall be maintained for 1 minute or until air bubbles cease to be given off by the water, whichever is the longer. Pressure shall then be increased to normal atmospheric pressure. Any evidence of bubbles emanating from within the device, or water entering the device, shall be considered
- (f) Observations. After each of the tests prescribed by this section, each device shall be examined for evidence of physical damage and for loss of trit-

ium or promethium-147. Any evidence of damage to or failure of any device which could affect containment of the tritium or promethium-147 shall be cause for rejection of the design if the damage or failure is attributable to a design defect. Loss of tritium or promethium-147 from each tested device shall be measured by wiping with filter paper an area of at least 100 square centimeters on the outside surface of the device, or by wiping the entire surface area if it is less than 100 square centimeters. The amount of tritium or promethium-147 in the water used in the hermetic seal and waterproof test prescribed by test paragraph (e) of this section shall also be measured. Measurements shall be made in an apparatus calibrated to measure tritium or promethium-147, as appropriate. The detection on the filter paper of more than 2,200 disintegrations per minute of tritium or promethium-147 per 100 square centimeters of surface wiped or in the water of more than 0.1 percent of the original amount of tritium or promethium-147 in any device shall be cause for rejection of the tested device.

[30 FR 8192, June 26, 1965]

## § 32.102 Schedule C—prototype tests for calibration or reference sources containing americium-241.

An applicant for a license pursuant to §32.57 shall, for any type of source which is designed to contain more than 0.005 microcurie of americium-241, conduct prototype tests, in the order listed, on each of five prototypes of such source, which contains more than 0.005 microcurie of americium-241, as follows:

- (a) *Initial measurement*. The quantity of radioactive material deposited on the source shall be measured by direct counting of the source.
- (b) Dry wipe test. The entire radioactive surface of the source shall be wiped with filter paper with the application of moderate finger pressure. Removal of radioactive material from the source shall be determined by measuring the radioactivity on the filter paper or by direct measurement of the radioactivity on the source following the dry wipe.
- (c) Wet wipe test. The entire radioactive surface of the source shall be

wiped with filter paper, moistened with water, with the application of moderate finger pressure. Removal of radioactive material from the source shall be determined by measuring the radioactivity on the filter paper after it has dried or by direct measurement of the radioactivity on the source following the wet wipe.

(d) Water soak test. The source shall be immersed in water at room temperature for a period of 24 consecutive hours. The source shall then be removed from the water. Removal of radioactive material from the source shall be determined by direct measurement of the radioactivity on the source after it has dried or by measuring the radioactivity in the residue obtained by evaporation of the water in which the source was immersed.

(e) *Dry wipe test.* On completion of the preceding test in this section, the dry wipe test described in paragraph (b) of this section shall be repeated.

(f) Observations. Removal of more than 0.005 microcurie of radioactivity in any test prescribed by this section shall be cause for rejection of the source design. Results of prototype tests submitted to the Commission shall be given in terms of radioactivity in microcuries and percent of removal from the total amount of radioactive material deposited on the source.

[30 FR 8192, June 26, 1965, as amended at 31 FR 15145, Dec. 2, 1966]

## § 32.103 Schedule D—prototype tests for ice detection devices containing strontium-90.

An applicant for a license pursuant to §32.61 shall conduct prototype tests on each of five prototype ice detection devices as follows:

- (a) Temperature-altitude test. The device shall be placed in a test chamber as it would be used in service. A temperature-altitude condition schedule shall be followed as outlined in Step 1 through Step 10 of § 32.101(a).
- (b) *Vibration tests.* The device shall be subjected to vibration tests as set forth in § 32.101(b).
- (c) *Shock test*. The device shall be subjected to shock test as set forth in §32.101(d).
- (d) Hermetic seal and waterproof test. On completion of all other tests pre-

scribed by this section, the device shall be immersed in 30 inches of water for 24 hours and shall show no visible evidence of physical contact between the water and the strontium-90. Absolute pressure of the air above the water shall then be reduced to 1 inch of mercury. Lowered pressure shall be maintained for 1 minute or until air bubbles cease to be given off by the water, whichever is the longer. Pressure shall then be increased to normal atmospheric pressure. Any visible evidence of physical contact between the water and the strontium-90 shall be considered leakage.

(e) Observations. After each of the tests prescribed by this section, each device shall be examined for evidence of physical damage and for loss of strontium-90. Any evidence of leakage or damage to or failure of any device which could affect containment of the strontium-90 shall be cause for rejection of the design if the damage or failure is attributable to a design defect. Loss of strontium-90 from each tested device shall be measured by wiping with filter paper an area of at least 100 square centimeters on the outside surface of the device, or by wiping the entire surface area if it is less than 100 square centimeters. The amount of strontium-90 in the water used in the hermetic seal and waterproof test prescribed in paragraph (d) of this section shall also be measured. The detection on the filter paper of more than 2,200disintegrations per minute of strontium-90 per 100 square centimeters of surface wiped or in the water of more than 0.1 percent of the original amount of strontium-90 in any device, shall be cause for rejection of the tested device.

[30 FR 9906, Aug. 10, 1965]

## Subpart C—Quality Control Sampling Procedures

## § 32.110 Acceptance sampling procedures under certain specific li-

(a) A random sample shall be taken from each inspection lot of devices licensed under §§ 32.14, 32.53, or 32.61 of this part for which testing is required pursuant to §§ 32.15, 32.55, or 32.62 in accordance with the appropriate Sampling Table in this section determined